

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NAKANO ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0163791	08-2003	Falbo et al.	716/2
	B	US-2003/0126582	07-2003	Kobayashi et al.	716/21
	C	US-6,664,010	12-2003	Ahrens et al.	430/5
	D	US-6,268,234	07-2001	Yoshida, Hiroyuki	438/60
	E	US-6,536,015	03-2003	Ono, Yusaku	716/2
	F	US-6,721,938	04-2004	Pierrat et al.	716/19
	G	US-6,815,148	11-2004	Matsumoto, Akira	430/313
	H	US-6,509,251	01-2003	Saito et al.	438/514
	I	US-3,998,639	12-1976	Feldman et al.	430/30
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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